

HAF1004(L), HAF1004(S)

Silicon P Channel MOS FET Series
Power Switching

HITACHI

ADE-208-629B (Z)

3rd. Edition
May 2002

Description

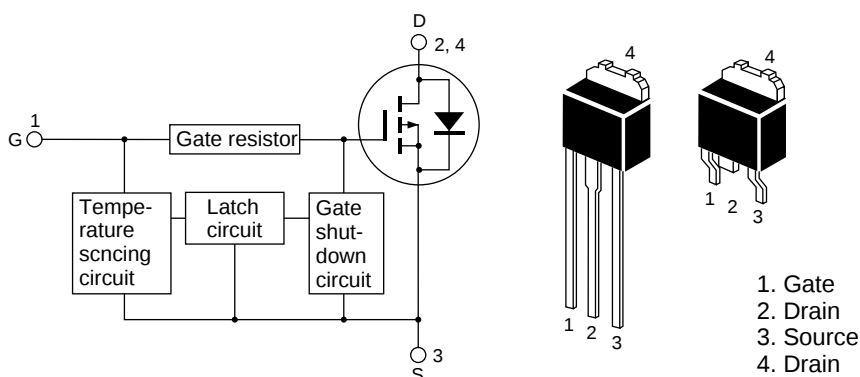
This FET has the over temperature shut-down capability sensing to the junction temperature. This FET has the built-in over temperature shut-down circuit in the gate area. And this circuit operation to shut-down the gate voltage in case of high junction temperature like applying over power consumption, over current etc.

Features

- Logic level operation (-4 to -6 V Gate drive)
- High endurance capability against to the short circuit
- Built-in the over temperature shut-down circuit
- Latch type shut-down operation (Need 0 voltage recovery)

Outline

DPAK-2



Absolute Maximum Ratings

(Ta = 25°C)

Item	Symbol	Ratings	Unit
Drain to source voltage	V _{DSS}	−60	V
Gate to source voltage	V _{GSS}	−16	V
Gate to source voltage	V _{GSS}	2.5	V
Drain current	I _D	−5	A
Drain peak current	I _D (pulse) ^{Note1}	−10	A
Body-drain diode reverse drain current	I _{DR}	−5	A
Channel dissipation	Pch ^{Note2}	20	W
Channel temperature	Tch	150	°C
Storage temperature	Tstg	−55 to +150	°C

Notes: 1. PW ≤ 10 μs, duty cycle ≤ 1 %
2. Value at Tc = 25°C

Typical Operation Characteristics

(Ta = 25°C)

Item	Symbol	Min	Typ	Max	Unit	Test Conditions
Input voltage	V _{IH}	−3.5	—	—	V	
	V _{IL}	—	—	−1.2	V	
Input current (Gate non shut down)	I _{IH1}	—	—	−100	μA	Vi = −8 V, V _{DS} = 0
	I _{IH2}	—	—	−50	μA	Vi = −3.5 V, V _{DS} = 0
	I _{IL}	—	—	−1	μA	Vi = −1.2 V, V _{DS} = 0
Input current (Gate shut down)	I _{IH(sd)1}	—	−0.8	—	mA	Vi = −8 V, V _{DS} = 0
	I _{IH(sd)2}	—	−0.35	—	mA	Vi = −3.5 V, V _{DS} = 0
Shut down temperature	Tsd	—	175	—	°C	Channel temperature
Gate operation voltage	Vop	−3.5	—	−12	V	

Electrical Characteristics

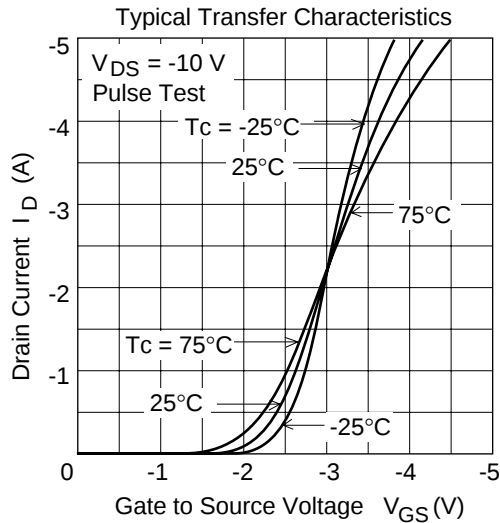
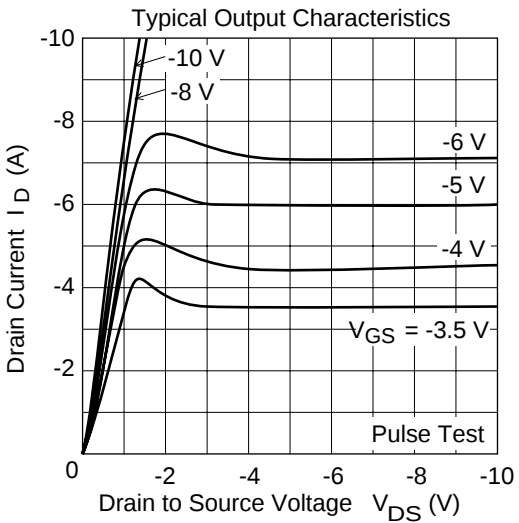
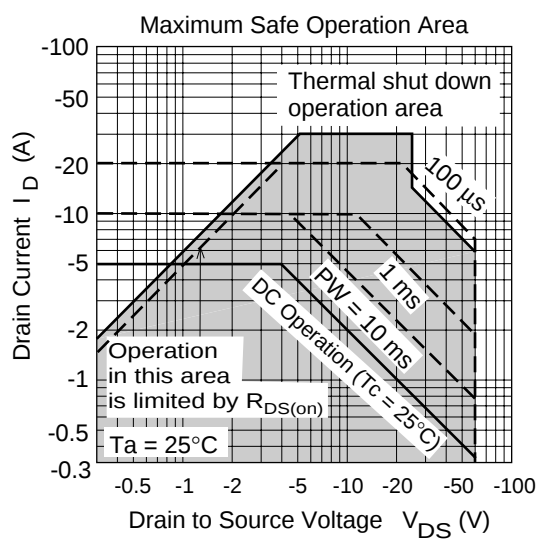
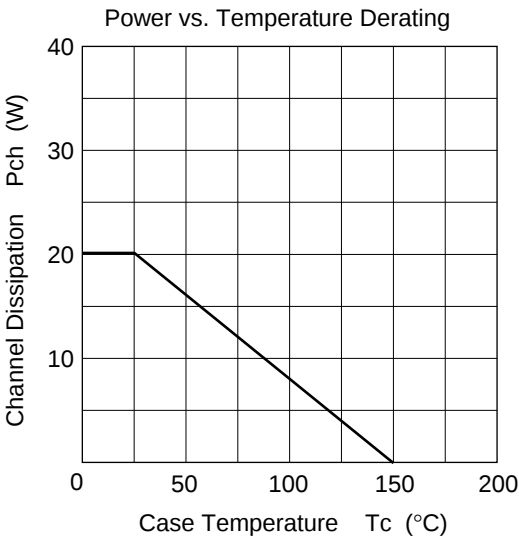
(Ta = 25°C)

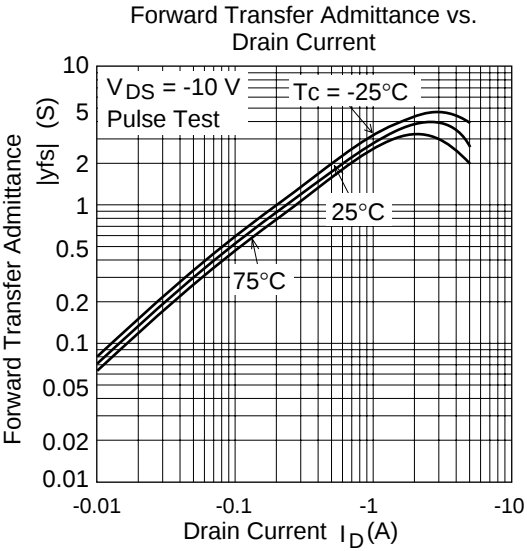
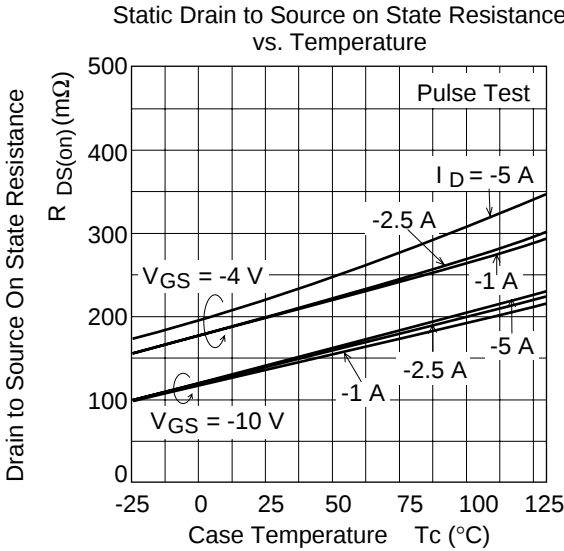
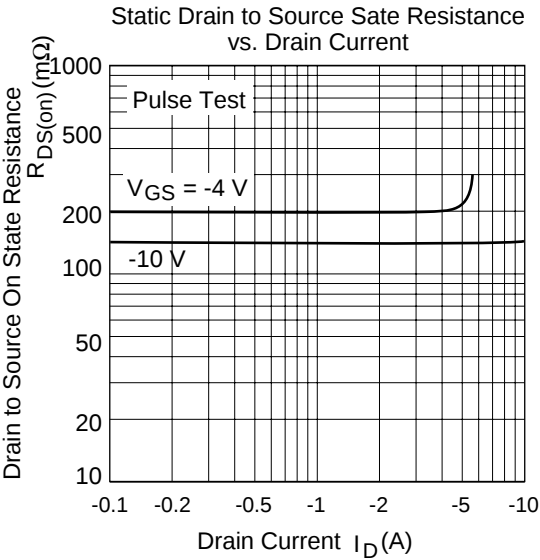
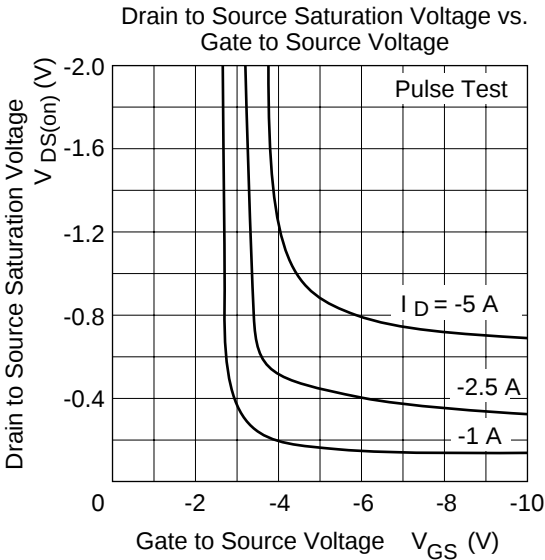
Item	Symbol	Min	Typ	Max	Unit	Test Conditions
Drain current	I_{D1}	-1.5	—	—	A	$V_{GS} = -3.5 \text{ V}$, $V_{DS} = -2 \text{ V}$
Drain current	I_{D2}	—	—	-10	mA	$V_{GS} = -1.2 \text{ V}$, $V_{DS} = -2 \text{ V}$
Drain to source breakdown voltage	$V_{(BR)DSS}$	-60	—	—	V	$I_D = -10 \text{ mA}$, $V_{GS} = 0$
Gate to source breakdown voltage	$V_{(BR)GSS}$	-16	—	—	V	$I_G = -800 \mu\text{A}$, $V_{DS} = 0$
Gate to source breakdown voltage	$V_{(BR)GSS}$	2.5	—	—	V	$I_G = 100 \mu\text{A}$, $V_{DS} = 0$
Gate to source leak current	I_{GSS1}	—	—	-100	μA	$V_{GS} = -8 \text{ V}$, $V_{DS} = 0$
	I_{GSS2}	—	—	-50	μA	$V_{GS} = -3.5 \text{ V}$, $V_{DS} = 0$
	I_{GSS3}	—	—	-1	μA	$V_{GS} = -1.2 \text{ V}$, $V_{DS} = 0$
	I_{GSS4}	—	—	100	μA	$V_{GS} = 2.4 \text{ V}$, $V_{DS} = 0$
Input current (shut down)	$I_{GS(OP)1}$	—	-0.8	—	mA	$V_{GS} = -8 \text{ V}$, $V_{DS} = 0$
	$I_{GS(OP)2}$	—	-0.35	—	mA	$V_{GS} = -3.5 \text{ V}$, $V_{DS} = 0$
Zero gate voltage drain current	I_{DSS}	—	—	-10	μA	$V_{DS} = -60 \text{ V}$, $V_{GS} = 0$
Gate to source cutoff voltage	$V_{GS(off)}$	-1.1	—	-2.25	V	$V_{DS} = -10 \text{ V}$, $I_D = -1 \text{ mA}$
Forward transfer admittance	$ y_{fs} $	2	4	—	S	$I_D = -2.5 \text{ A}$, $V_{DS} = -10 \text{ V}$ ^{Note3}
Static drain to source on state resistance	$R_{DS(on)}$	—	200	340	m Ω	$I_D = -2.5 \text{ A}$, $V_{GS} = -4 \text{ V}$ ^{Note3}
Static drain to source on state resistance	$R_{DS(on)}$	—	140	200	m Ω	$I_D = -2.5 \text{ A}$, $V_{GS} = -10 \text{ V}$ ^{Note3}
Output capacitance	C_{oss}	—	326	—	pF	$V_{DS} = -10 \text{ V}$, $V_{GS} = 0$, $f = 1 \text{ MHz}$
Turn-on delay time	$t_{d(on)}$	—	2	—	μs	$V_{GS} = -5 \text{ V}$, $I_D = -2.5 \text{ A}$, $R_L = 12 \Omega$
Rise time	t_r	—	7.6	—	μs	
Turn-off delay time	$t_{d(off)}$	—	3.2	—	μs	
Fall time	t_f	—	3.2	—	μs	
Body-drain diode forward voltage	V_{DF}	—	-0.9	—	V	$I_F = -5 \text{ A}$, $V_{GS} = 0$
Body-drain diode reverse recovery time	t_{rr}	—	77	—	ns	$I_F = -5 \text{ A}$, $V_{GS} = 0$ $diF/dt = 50 \text{ A}/\mu\text{s}$
Over load shut down	t_{os1}	—	8.4	—	ms	$V_{GS} = -5 \text{ V}$, $V_{DD} = -16 \text{ V}$
operation time ^{Note4}	t_{os2}	—	2.4	—	ms	$V_{GS} = -5 \text{ V}$, $V_{DD} = -24 \text{ V}$

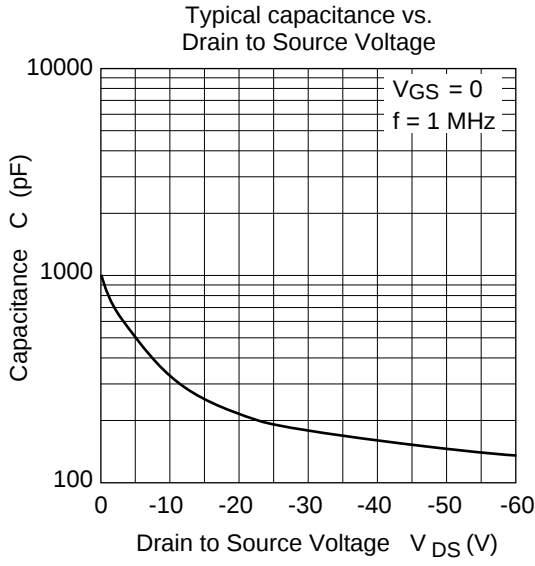
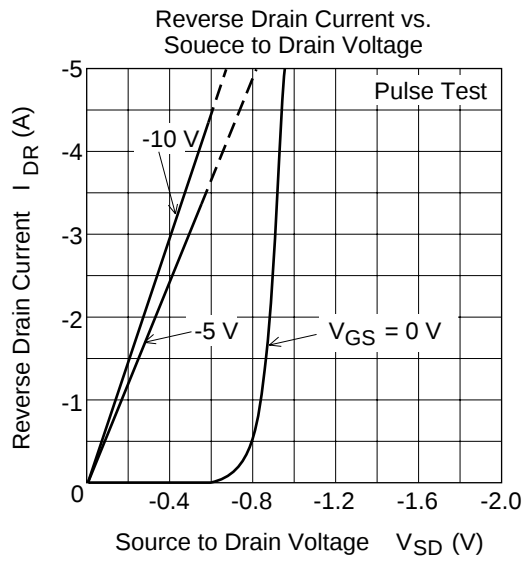
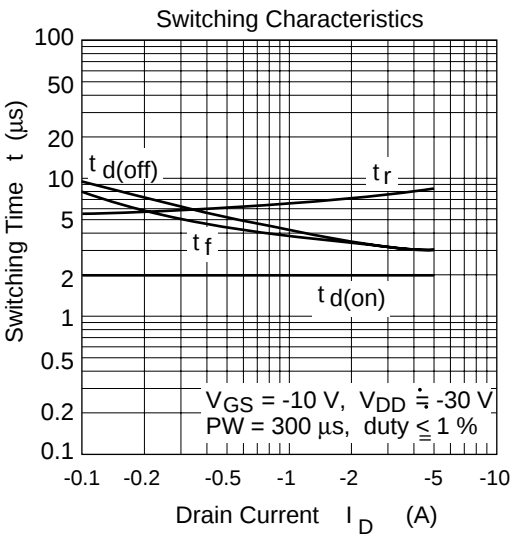
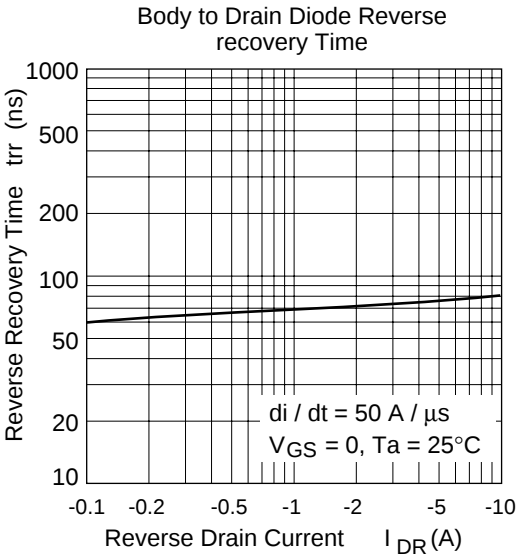
Notes: 3. Pulse test

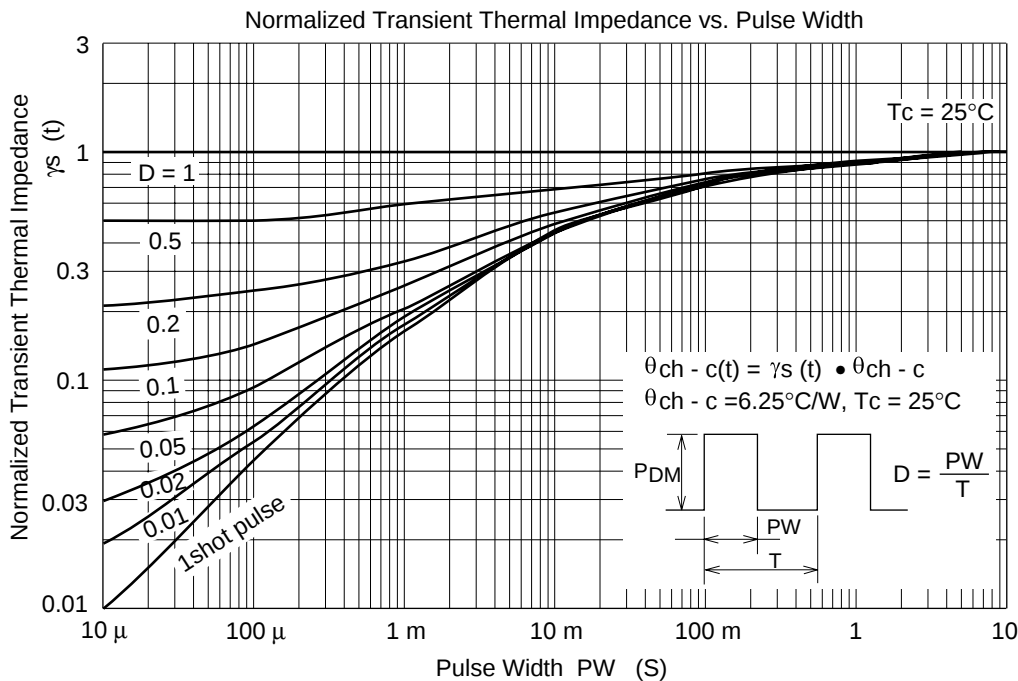
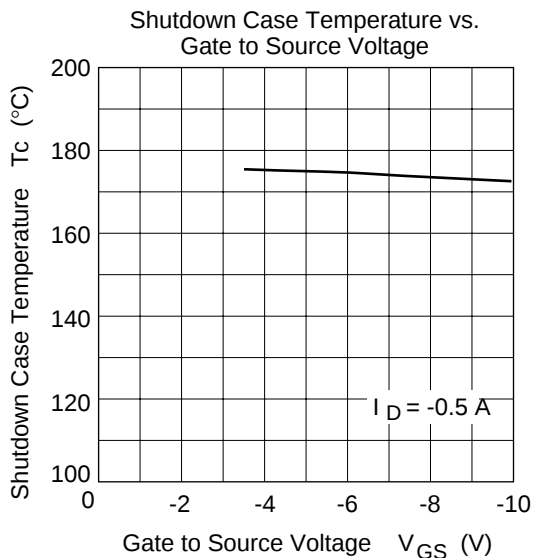
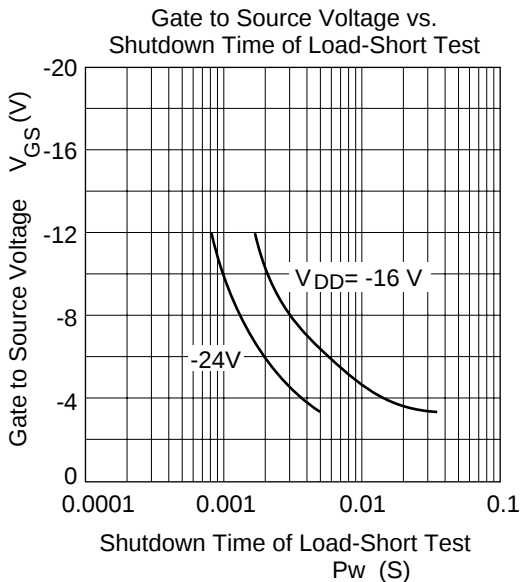
4. Including the junction temperature rise of the over loaded condition

Main Characteristics



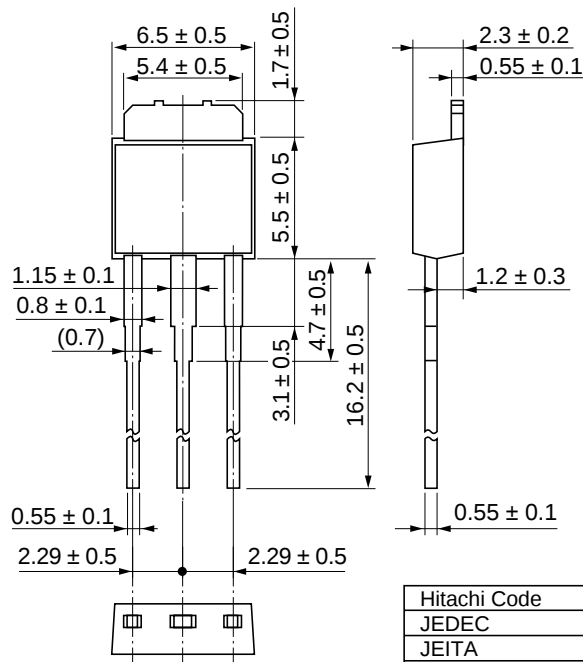






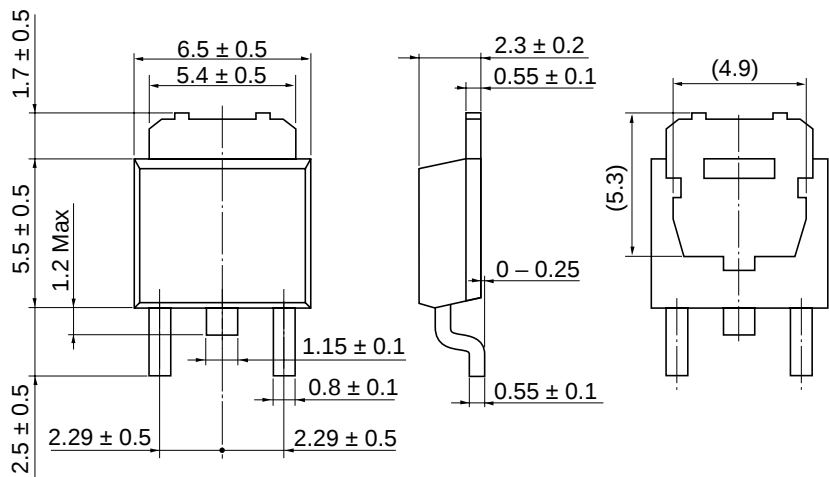
Package Dimensions

As of January, 2002
Unit: mm



Hitachi Code	DPAK (L)-(2)
JEDEC	—
JEITA	—
Mass (reference value)	0.42 g

As of January, 2002
Unit: mm



Hitachi Code	DPAK (S)-(1),(2)
JEDEC	—
JEITA	Conforms
Mass (reference value)	0.28 g

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